



Application of Artificial Neural Network in Non-destructive Testing

Guest Editor:

Dr. Gholam Hossein Roshani

Electrical Engineering
Department, Kermanshah
University of Technology,
Kermanshah 6715685420, Iran

Deadline for manuscript
submissions:

closed (15 September 2023)

Message from the Guest Editor

Dear Colleagues,

Artificial Neural Network (ANN) as a mathematical method has powerful role in solving various engineering and management problems for different purposes such as classification and prediction. The necessity of this efficient tool is clearly seen in nonlinear and complex systems. Application of other numerical methods such as feature extraction in time, frequency and time-frequency domain, feature reduction, feature selection, correlation analysis and etc. beside of ANN can improve the efficiency of Non-Destructive Testing (NDT) with any basis for obtaining better result for desired purposes. This Special Issue of Applied Sciences will provide a forum for discussing exciting research on applying different kinds of ANNs such as Feed Forward NN, Radial Basis Function, Kohonen Self Organizing NN, Support Vector Machine, Group Method of Data Handling, Recurrent NN, Convolutional NN and etc. in a variety of domains specially complex problems of NDT.

Both original research articles and comprehensive review papers are welcome.





an Open Access Journal by MDPI

Editor-in-Chief

Prof. Dr. Flavio Canavero

Department of Electronics and
Telecommunications,
Politecnico di Torino, 10129
Torino, Italy

Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

Author Benefits

Open Access: free for readers, with [article processing charges \(APC\)](#) paid by authors or their institutions.

High Visibility: indexed within [Scopus](#), [SCIE \(Web of Science\)](#), [CAPus / SciFinder](#), [Inspec](#), [Ei Compendex](#) and [other databases](#).

Journal Rank: JCR - Q2 (Engineering, Electrical and Electronic) / CiteScore - Q1 (Electrical and Electronic Engineering)

Contact Us

Electronics Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland

Tel: +41 61 683 77 34
www.mdpi.com

mdpi.com/journal/electronics
electronics@mdpi.com
[X@electronicsMDPI](#)